Se	arcn No	otes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/694,220	KIM ET AL.	
Examiner	Art Unit	
Tianije Chen	2627	

	SEARCHED		
Class	Subclass	Date	Examiner
369	300		
	221		
	13.13		
	44.19		
	44.23		
360	126		
310	309		
720	681	8/28/2006	TJ
		l	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SE	ARCH STRATEGY	′)
	DATE	EXMR
East Report	8/28/2006	TJ